

<b>Project Title -19</b>	<b>A study on Extra – Sensitive yarn imperfections on Fabric Appearance</b>
<b>Principal Investigator</b>	Arindam Basu
<b>Cost</b>	Rs.26.05 lakhs
<b>Date of Commencement</b>	01.09.1999
<b>Duration</b>	24 Months
<b>Date of Completion</b>	Sep 2001
<b>Abstract</b>	Generally, yarn imperfections are measured by capacitance based evenness testers and they are classified as thin places, thick places and neps. Conventionally, for the above classification, -50%, +50% and +200% respectively are chosen as sensitivity levels. An attempt has been to find out the influence of the imperfections measured at more sensitive level on the yarn and fabric appearance. Also, the influence of various process parameters such as card production rate, settings between flat and cylinder on card, hank of card sliver, comber noil extraction on the extra sensitive imperfections and the fabric appearance has been studied.
<b>Highlights</b>	<ul style="list-style-type: none"> <li>▪ The study revealed that the prediction of yarn appearance becomes more accurate when extra sensitive imperfections (-40%, +35%, +140%) are included in the prediction along with conventional imperfections (-50%, +50%, +200%) and correlation coefficient varies between 0.77 and 0.93.</li> </ul>
<b>Area of applicability</b>	Spinners
<b>Target beneficiaries</b>	<ul style="list-style-type: none"> <li>• The study of findings were disseminated to SITRA member mills</li> <li>• Mills are making use of these findings to produce better quality yarns and thereby better quality fabrics</li> </ul>
<b>Status</b>	Completed